## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination YOSHIKAWA, KEN Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,675,010 B1	01-2004	Yeh, Hao Ming	455/422.1
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-		•	
	J	US-			
	K	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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